### EE 330 Lecture 13

### Devices in Semiconductor Processes

- Resistors
- Diodes
- Capacitors
- MOSFETs
- BJTs

### Fall 2024 Exam Schedule

Exam 1 Friday Sept 27

**Review from Last Lecture**

## Basic Semiconductor Processes

MOS (Metal Oxide Semiconductor)



- Basic Device: MOSFET
- Niche Device: MESFET
- Other Devices: Diode

BJT (Bipolar Junction Transistor) JFET (Junction Field Effect Transistor) Resistors Capacitors Schottky Diode

# Basic Semiconductor Processes

### Bipolar

- $\mathbf{1}$ .  $T^2L$
- 2. ECL
- 3.  $1^2L$
- 4. Linear Ics

- Basic Device: BJT (Bipolar Junction Transistor)
- Niche Devices: HBT (Heterojunction Bipolar Transistor)
- Other Devices: Diode

Resistor Capacitor Schottky Diode JFET (Junction Field Effect Transistor)

# Basic Semiconductor Processes

Other Processes

- Thin and Thick Film Processes
	- Basic Device: Resistor
- BiMOS or BiCMOS
	- Combines both MOS & Bipolar Processes
	- Basic Devices: MOSFET & BJT
- SiGe
	- BJT with HBT implementation
- SiGe / MOS
	- Combines HBT & MOSFET technology
- SOI / SOS (Silicon on Insulator / Silicon on Sapphire)
- Twin-Well & Twin Tub CMOS
	- Very similar to basic CMOS but more optimal transistor char.

### **Review from Last Lecture**

### Devices in Semiconductor Processes

- Standard CMOS Process
	- MOS Transistors
		- n-channel
		- p-channel
	- Capacitors
	- Resistors
	- Diodes
	- BJT ( decent in some processes)
		- npn
		- pnp
	- JFET (in some processes)
		- n-channel
		- p-channel
- Standard Bipolar Process
	- BJT
		- npn
		- pnp
	- JFET
		- n-channel
		- p-channel
	- Diodes
	- Resistors
	- Capacitors
- Niche Devices
	- Photodetectors (photodiodes, phototransistors, photoresistors)
	- MESFET
	- HBT
	- Schottky Diode (not Shockley)
	- MEM Devices
	- TRIAC/SCR
	- ….

## Basic Devices

#### • Standard CMOS Process



- Niche Devices
	- Photodetectors (photodiodes, phototransistors, photoresistors)
	- MESFET
	- HBT
	- Schottky Diode (not Shockley)
	- MEM Devices
	- TRIAC/SCR – ….

**Some Consideration in This Course**

## Basic Devices and Device Models

- Resistor
- Diode
- Capacitor
- MOSFET
- BJT
- 
- 

## Basic Devices and Device Models



- Diode
- Capacitor
- MOSFET
- BJT

Resistors were discussed when considering interconnects so will only be briefly reviewed here

# Resistors

- Generally thin-film devices
- Almost any thin-film layer can be used as a resistor
	- Diffused resistors
	- Poly Resistors
	- Metal Resistors
	- "Thin-film" adders (SiCr or NiCr)
- Subject to process variations, gradient effects and local random variations
- Often temperature and voltage dependent
	- Ambient temperature
	- Local Heating
- Nonlinearities often a cause of distortion when used in circuits
- Trimming possible resistors
	- Laser, links, switches

Have already modeled resistance as an interconnect Modeling is the same as for a resistor so will briefly review

## Resistor Model



**V R** <sup>=</sup> Model:

# Resistivity

• Volumetric measure of conduction capability of a material



### Sheet Resistance



for homogeneous materials,  $R$  is independent of W, L, R

### Relationship between  $\rho$  and R.



Number of squares,  $N_{\rm s}$ , often used instead of L / W in determining resistance of film resistors

 $R = R_1N_S$ 



 $R = ?$ 





 $R = ?$ 



**R = R• (8.4)**  $R = ?$  $N_s = 8.4$ 

## Corners in Film Resistors



Rule of Thumb: .55 squares for each corner

### Determine R if  $R = 100 \Omega /$





 $N_S = 17.1$  $R = (17.1) R$  $R = 1710 \Omega$ 

### Resistivity of Materials used in Semiconductor Processing

- Cu:  $1.7E-6 \Omega$ cm
- Al:  $2.7E-6 \Omega$ cm
- Gold:  $2.4E-6 \Omega$ cm
- Platinum:  $1.1E-5$   $\Omega$ cm
- Polysilicon: 1E-2 to 1E4  $\Omega$ cm\*
- n-Si: typically .25 to 5  $\Omega$ cm\* (but larger range possible)
- intrinsic Si:  $2.5E5$   $\Omega$ cm
- SiO<sub>2</sub>:  $E14\ \Omega \text{cm}$

<sup>\*</sup> But fixed in a given process

### http://www.cleanroom.byu.edu/ResistivityCal.phtml

#### **Resistivity & Mobility Calculator/Graph for** Various Doping Concentrations in Silicon



Calculations are for a silicon substrate.



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#### **Resistivity & Mobility Calculator/Graph for** Various Doping Concentrations in Silicon



Calculations are for a silicon substrate.



# Temperature Coefficients

Used for indicating temperature sensitivity of resistors & capacitors **For a resistor:**

$$
TCR = \left(\frac{1}{R}\frac{dR}{dT}\right)_{\text{op. temp}}
$$
  $\bullet$  10<sup>6</sup> ppm/<sup>°</sup>C

This differential eqn can easily be solved if TCR is a constant  $(T_2)$  = R $(T_1)$ TCR 1 0  $\rm T$ -T  $27 - 11$ 6 2 1  $R(T_{2}) = R(T$ −  $=$  KU, le If x is small,  $e^x \cong 1+x$ 

It follows that If  $TCR*(T_2-T_1)$  is small,

$$
R(T_2) \approx R(T_1) \left[ 1 + (T_2 - T_1) \frac{TCR}{10^6} \right]
$$

Identical Expressions for Capacitors

# Voltage Coefficients

Used for indicating voltage sensitivity of resistors & capacitors **For a resistor:**

$$
VCR = \left(\frac{1}{R}\frac{dR}{dV}\right)_{ref \, voltage} \bullet 10^6 \, ppm/V
$$

This diff eqn can easily be solved if VCR is a constant

$$
R(V_2) = R(V_1) e^{\frac{V_2 - V_1}{10^6} VCR}
$$

It follows that If  $VCR*(V_2-V_1)$  is small,

$$
R(V_2) \approx R(V_1) \left[1 + (V_2 - V_1) \frac{VCR}{10^6}\right]
$$

### Identical Expressions for Capacitors

### Temperature and Voltage Coefficients

- Temperature and voltage coefficients often quite large for diffused resistors
- Temperature and voltage coefficients often quite small for poly and metal film (e.g. SiCr) resistors



**VV** 

(relative accuracy much better and can be controlled by designer)

From:F. Maloberti : Design of CMOS Analog Integrated Circuits - "Resistors, Capacitors, Switches"

### **MOS Passive RC Component Typical Performance Summary**





### Table 2.4-1 Approximate Performance Summary of Passive Components in a 0.18 pm **CMOS Process**

From Allen Holberg Third Edition

### **MOS Passive RC Component Performance Summary**





### **EECS240 Lingkai Kong**

### How does TCR of Integrated Resistors Compare with Low-Cost Discrete Resistors?

Metal film resistors are available with tolerances of 0.1,  $0.25$ , 0.5, 1 and 2%. The temperature coefficient of resistance (TCR) is usually between 50 and 100 ppm/°C.



Integrated resistors typically have a much larger TCR but there are some special processes that provide resistors with excellent thermal stability (\$\$\$)

Example: Determine the percent change in resistance of a 5K Polysilicon resistor as the temperature increases from  $30^{\circ}$ C to  $60^{\circ}$ C if the TCR is constant and equal to 1500 ppm/°C

$$
R(T_2) \cong R(T_1) \left[ 1 + (T_2 - T_1) \frac{TCR}{10^6} \right]
$$
  

$$
R(T_2) \cong R(T_1) \left[ 1 + (30^{\circ}C) \frac{1500}{10^6} \right]
$$
  

$$
R(T_2) \cong R(T_1) [1 + .045]
$$

 $R(\mathcal{T}_2^{})$   $\cong R(\mathcal{T}_1)[1.045]$ 

Thus the resistor increases by 4.5%

Did not need  $R(T_1)$  to answer this question !

What is  $R(T_1)$  as stated in this example ?  $5K$ ? It is around 5K but if we want to be specific, would need to specify T

## Basic Devices and Device Models

• Resistor



- Capacitor
- MOSFET
- BJT

# **Periodic Table of the Elements**



http://www.dayah.com/periodic/Images/periodic%20table.png





All elements in group IV have 4 valence-band electrons



All elements in group III have 3 valence-band electrons



### http://www.oftc.usyd.edu.au/edweb/devices/semicdev/doping4.html



**Serves as an "donor " of electrons**

**Acts as an n-type impurity when used as a silicon dopant**  All elements in group V have 5 valence-band electrons









### Silicon Dopants in Semiconductor Processes

**B** (Boron) widely used dopant for creating p-type regions

- **P** (Phosphorus) widely used dopant for creating n-type regions (bulk doping, diffuses fast)
- **As** (Arsenic) widely used dopant for creating n-type regions (Active region doping, diffuses slower)

# Diodes (pn junctions)





If doping levels identical, depletion region extends equally into n-type and p-type regions



Extends farther into p-type region if p-doping lower than n-doping



Separating n-type and p-type regions

Extends farther into n-type region if n-doping lower than p-doping



- Positive voltages across the p to n junction are referred to forward bias
- Negative voltages across the p to n junction are referred to reverse bias
- As forward bias increases, depletion region thins and current starts to flow
- Current grows very rapidly as forward bias increases
- Current is very small under revere bias



- As forward bias increases, depletion region thins and current starts to flow
- Current grows very rapidly as forward bias increases



### pn Junctions  $I_{\mathsf{D}}$  $V_D$ Simple Diode Model:  $V_D$ ID forward bias reverse bias

pn junction serves as a "rectifier" passing current in one direction and blocking it in the other direction



Analysis based upon "passing current" in one direction and " blocking current" in the other direction



# Stay Safe and Stay Healthy !

# End of Lecture 13